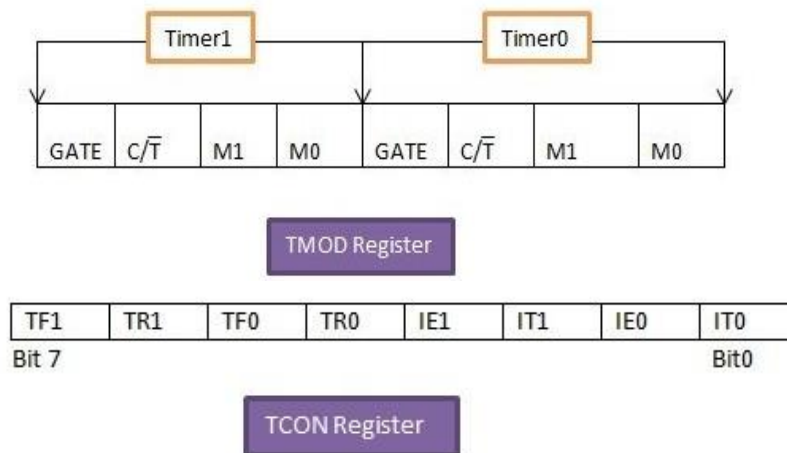


- iii) Construct the delay loop with appropriate timer flag setting
- iv) Access and configure relevant pin as needed
- v) Call back delay loop from the main function as needed



For level triggered: interrupt is enabled for a low at INTx pin.

For edge triggered: interrupt is enabled for a high to low transition at INTx pin.

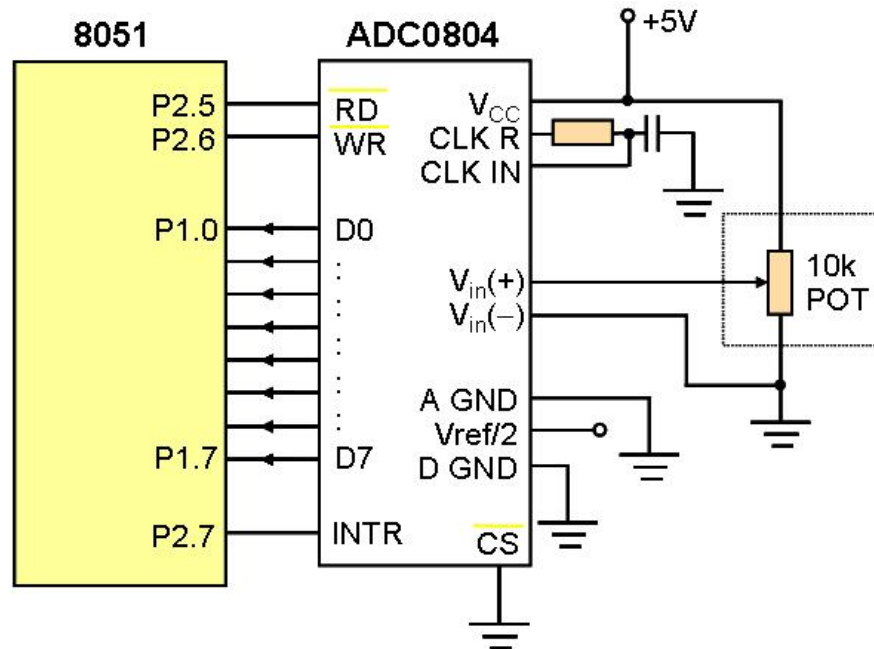
TCON REGISTER:



2. Answer all the questions given below

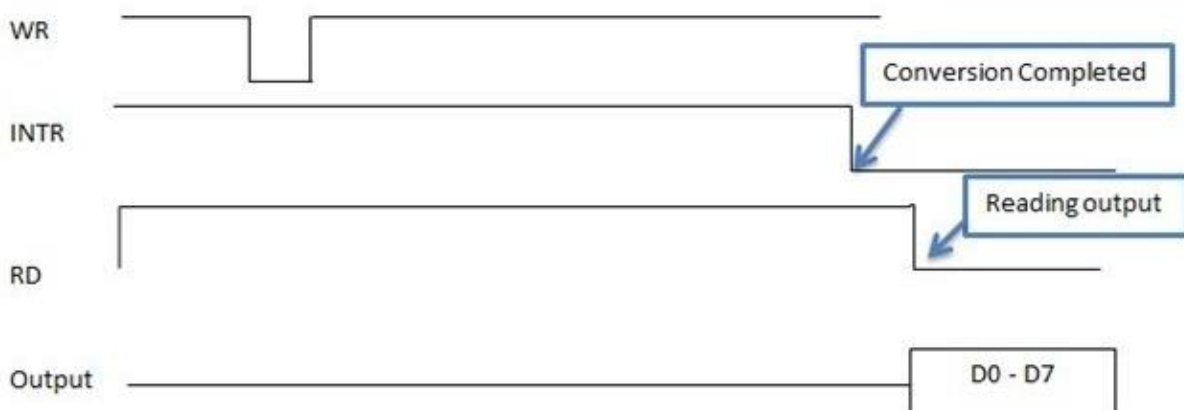
(a) What are the two main steps for analog to digital conversion? Show that the quantization error increases as the range of voltage levels to be sensed increases. Use 3 bit ADC as an example [2.5+2.5]

(b) Consider the following 8051 interfacing problem. [1+1+1+1+1]



The **delay between consecutive analog to digital conversion** will be dynamically adjusted. If the analog reading (V_{analog}) goes $\geq V_{\text{CC}}/2$, delay is 40 ms while if goes $< V_{\text{CC}}/2$, delay is 20 ms

- Initialize the digital reading input port of 8051
- Define and configure WR, RD and INTR pins
- Define ADC routine
- Call back delay function in ADC routine as needed. The off time for WR is 10 ms as shown below
- Conditional call back in main function as determined from the analog to digital code conversion equation given below. You can use global variable



Hints:

-function to create required delay

```
void delay(unsigned int msec ) // Delay function
{
inti,j ;
for(i=0;i<msec;i++)
for(j=0; j<1275; j++);
}
```

- Equation to derive analog value read

$V_{\text{analog}} = \text{ADC code} * \text{LSB in decimal}$

Full scale = 5V

N=8 bits

$\text{LSB} = \text{Full scale} / 2^N$

N=8

Full scale=5-0=5 (for 5V VCC)

ADC code: **0000 0000** to **1111 1111** in binary